

IN THE CLAIMS

Please amend the claims as follows.

1. (Currently Amended) A test device comprising:

an element having a surface for electrically contacting a contact associated with a secondary side of a device under test, the element further comprising features for contacting a ground plane dimensioned to prevent interference from radio signals of a selected frequency, the features for contacting a ground plane include a plurality of pointed peaks separated by valleys wherein the height of the peaks are dimensioned to prevent passage of radio signals of a selected frequency; and

a probe having a free end positioned for electrically contacting a contact associated with a primary side of the device under test, wherein the element shields the probe.

2. (Currently Amended) The test device of claim 1 wherein ~~the element having the surface to contact the primary side includes~~ features for contacting a ground plane ~~on the~~ are associated with a secondary side of the device under test.

3. (Original) The test device of claim 1 wherein the length of the probe is greater than the length of the element having a surface for contacting the first plane.

4. (Currently Amended) The test device of claim ~~1~~ 5 ~~further comprising at least one other test probe adapted to contact an electrical contact in a first plane of a device under test~~ 1 ~~wherein the element shields the probe.~~

5. (Original) The test device of claim 1 wherein the element surrounds the probe to shield the probe.

- 6.-7. (Canceled)

8. (Original) The test device of claim 7 wherein the element includes a cylindrical portion surrounding a portion of the probe.

9. – 14. (Canceled)

15. (Currently Amended) ~~An electrical~~ The testing device of claim 1 further comprising:

a first plane; and

a second plane, the features for contacting a ground plane located in the first plane and the free end of the probe located in a second plane.

~~a first at test probe adapted to contact an electrical contact in a first plane of a device under test; and~~

~~a second test probe, the second test probe further comprising:~~

~~an element having a surface for contacting a first plane of the device under test; and~~

~~a free end positioned in a second plane adapted to contact an electrical element in the second plane of the device under test.~~

16. (Currently Amended) ~~The electrical~~ testing device of claim 15 further comprising a fixture having a nest adapted to receive an electrical device having elements to be tested on a first plane and on a second plane.

17. (Currently Amended) ~~The electrical~~ testing device of claim 16 wherein the electrical device is a circuit board.

18. - 21. (Canceled)

22. (Currently Amended) ~~The electrical~~ testing device of claim 15 further comprising a fixture having a nest adapted to receive an electrical device that includes:

a printed circuit board further including:

a primary side; and

a secondary side;

a component having a main body, the component attached to the primary side of the printed circuit board, the component further including a pad on the main body of the component, the pad on the component positioned between the main body of the component and the primary side of the printed circuit board;

a ground plane connection surface attached to the secondary side of the printed circuit board, the printed circuit board having an opening therein positioned near the pad on the main body of the component.

23. - 28. (Canceled)

29. (Currently Amended) The test device of claim [[28]] 1 wherein the element includes a cylindrical portion surrounding a portion of the probe.